

Appln. No. 10/527,108
Amdt. dated June 7, 2006
Reply to Office Action dated April 4, 2006

AMENDMENTS TO THE CLAIMS:

Please amend claims 1-8 as follows. The following listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims:

Claim 1 (Currently Amended). A test device for testing an integrated circuit comprising a plurality of contacts, called a test circuit, intended to be tested with the aid of a test printed circuit, called a main circuit, the test device

5 comprising:

an insulating, non-conductive membrane of a soft material having two opposite surfaces; ~~covered by~~

two conductive layers each covering a respective one of the two opposite surfaces of said non-conductive membrane;

10 ~~interconnected by~~

connection means for interconnecting said two conductive layers, said two conductive layers being adapted and intended to come into contact with the test circuit and the main circuit respectively, under the influence of a pressing force exerted
15 during the test between the test circuit and the main circuit

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deforming the test device; and [[,]]

protrusions ~~being~~ arranged on at least one of said two
conductive layers according to a predefined pattern as a function
of said plurality of contacts of the test circuit, so as to
20 ensure a contact quality between said at least one layer and the
test circuit or the main circuit in contact with said at least
one layer, under the influence of said pressing force.

Claim 2 (Currently Amended). A test device as claimed in
claim 1, ~~in which~~ wherein said connection means are ~~provided by~~
metallized holes passing through said membrane and ~~the~~ said two
layers.

Claim 3 (Currently Amended). A test device as claimed in
claim 1, ~~in which~~ wherein ^{test} the device has a thickness less than or
equal to 0.4 ~~millimeter~~ millimeters.

Claim 4 (Currently Amended). A test device as claimed in
claim 1, ~~in which the~~ wherein said non-conductive membrane has a
thickness less than or equal to 0.1 millimeter.

Claim 5 (Currently Amended). A test device as claimed in
claim 1, ~~in which the~~ wherein said protrusions have a height
larger than or equal to 45 micrometers.

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Claim 6 (Currently Amended). A test device as claimed in claim 1, ~~in which the~~ wherein said protrusions have a diameter relative to the surface of said contacts.

Claim 7 (Currently Amended). A test device as claimed in claim 1, ~~in which the~~ wherein said membrane is made of Kapton.

Claim 8 (Currently Amended). A test device as claimed in claim 1, ~~in which the~~ wherein said protrusions are arranged in pairs on each of ~~the~~ said two layers, each element of the pair being situated on an opposite layer on either side of ~~the~~ said connection means, so as to perform a change of the soft membrane under the influence of said pressing force.

Claim 9 (Withdrawn). A test method comprising the delivery of an integrated circuit called test circuit in a given housing from a set of different types of housings, intended to be tested by a test circuit, called main circuit, and a set of test devices as claimed in claim 1 corresponding to said set of housings adapted to said test circuit as a function of each type of housing considered.

Claim 10 (Withdrawn). A test method as claimed in claim 9, in which each test device comprises on a first surface, called

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standard surface, a standard conductive layer adapted to the main
circuit and on a second surface, called specific surface, a
5 specific conductive layer adapted to a predefined type of
housing.

Claim 11 (New). A test device as claimed in claim 1,
wherein said protrusions are in the form of a truncated cone.

Claim 12 (New). A test device as claimed in claim 1,
wherein said protrusions are engraved onto said at least one of
said two conductive layers.

Claim 13 (New). A test device as claimed in claim 1,
wherein said protrusions are arranged on both of said two
conductive layers.

Claim 14 (New). A test device as claimed in claim 13,
wherein said protrusions on one of said two conductive layers are
offset from said protrusions on the other one of said two
conductive layers with said connection means being arranged
5 between said protrusions.

Claim 15 (New). A test device as claimed in claim 1,
wherein said two conductive layers comprise two layers of

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conductive tracks.

Claim 16 (New). A test device for testing an integrated circuit comprising a plurality of contacts, called a test circuit, intended to be tested with the aid of a test printed circuit, called a main circuit, the test device comprising:

5 an insulating, non-conductive membrane of a soft material having two opposite surfaces;

two conductive layers each arranged on a respective one of the opposite surfaces of said membrane;

a connection device which interconnects said two conductive
10 layers, said two conductive layers being adapted to contact with the test circuit and the main circuit respectively, under the influence of a pressing force exerted during the test between the test circuit and the main circuit deforming the test device, said connection device being metallized holes passing through said
15 membrane and through said two conductive layers; and

protrusions arranged on at least one of said two conductive layers according to a predefined pattern as a function of said plurality of contacts of the test circuit, so as to ensure a contact quality between said at least one layer and the test
20 circuit or the main circuit in contact with said at least one layer, under the influence of said pressing force.

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Claim 17 (New). A test device as claimed in claim 16,
wherein said protrusions are arranged on both of said two
conductive layers.

Claim 18 (New). A test device as claimed in claim 17,
wherein said protrusions are arranged in pairs with one of said
metallized holes being situated therebetween, a first protrusion
of each pair being situated on a first one of said two conductive
5 layers on one side of a respective one of said metallized holes
and a second protrusion of each pair being situated on a second
one of said two conductive layers on an opposite side of said
respective one of said metallized holes whereby said protrusions
are thereby offset from one another.

Claim 19 (New). A test device as claimed in claim 16,
wherein said two conductive layers comprise two layers of
conductive tracks.

Claim 20 (New). A test device as claimed in claim 16,
wherein said two conductive layers cover the respective one of
the opposite surfaces of said membrane.